



IGBT³ Chip

FEATURES:

- 600V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- · easy paralleling

This chip is used for:

- power module
- discrete components



Applications:

drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC28T60	600V	50A	6.57 x 4.2 mm ²	sawn on foil	Q67050- A4337-A101

MECHANICAL PARAMETER:

Raster size	6.57 x 4.2				
Emitter pad size	2.166 x 3.401 2.432 x 3.401	mm ²			
Gate pad size	0.817 x 1.52				
Area total / active	27.6 / 20				
Thickness	70	μm			
Wafer size	150	mm			
Flat position	90	deg			
Max. possible chips per wafer	457 pcs				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm AlSiCu				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, <500μm				
Reject ink dot size	Ø 0.65mm ; max 1.2mm				
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



SIGC28T60

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, T_j = 25 °C	V _{CE}	600	V	
DC collector current, limited by T _{jmax}	I _C	1)	Α	
Pulsed collector current, t_p limited by T_{jmax}	<i>I</i> _{cpuls} 150		А	
Gate emitter voltage	V_{GE}	±20	V	
Operating junction and storage temperature	$T_{\rm j},~T_{\rm stg}$	-40 +175	°C	
SC data, V _{GE} = 15V, V _{CC} = 360V	Tvj = 150°C	tp	6	μs
	Tvj = 25°C	'	8	μ.σ

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), $T_{\rm j}$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
i arameter		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0 V , I_{C} = 4 m A	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =50A	1.05	1.45	1.85	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I_C =800 μ A , V_{GE} = V_{CE}	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =600V , V_{GE} =0V			2.6	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	R_{Gint}			none		Ω

ELECTRICAL CHARACTERISTICS (verified by design/characterization):

Parameter	Symbol	Conditions	Value			Unit
raiametei		Conditions	min.	typ.	max.	Oilit
Input capacitance	Ciss	V _{CE} =25V,		3140		pF
Output capacitance	Coss	$V_{GE}=0V$,		200		
Reverse transfer capacitance	C _{rss}	f=1MHz		93		

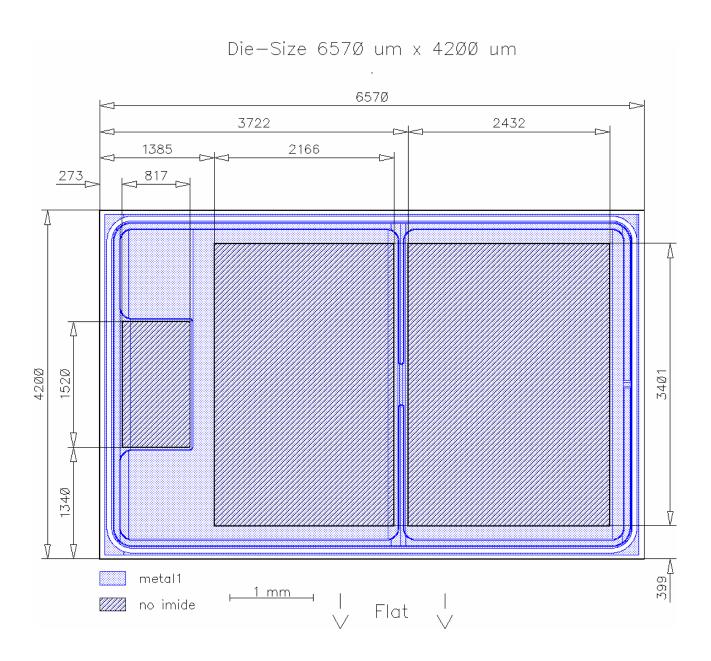
SWITCHING CHARACTERISTICS (verified by design/characterization), inductive load

Parameter	Symbol	Conditions	Value 2)			Unit
raiametei	Syllibol	Conditions	min.	typ.	max.	Oilit
Turn-on delay time	$t_{d(on)}$	<i>T</i> _j =125°C		22		ns
Rise time	t _r	$V_{\rm CC} = 300 \text{V}$		16		
Turn-off delay time	$t_{d(off)}$	I _C =50A, V _{GE} =-15/15V,		180		
Fall time	t_{f}	$R_{\rm G}$ = 8.2 Ω		50		

 $^{^{2)}}$ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





SIGC28T60

This chip data sheet refers to the device data sheet DESCRIPTION: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883 Test-Normen Villach/Prüffeld

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